

Modelling the response of microbulk Micromegas in Xe-TMA admixtures

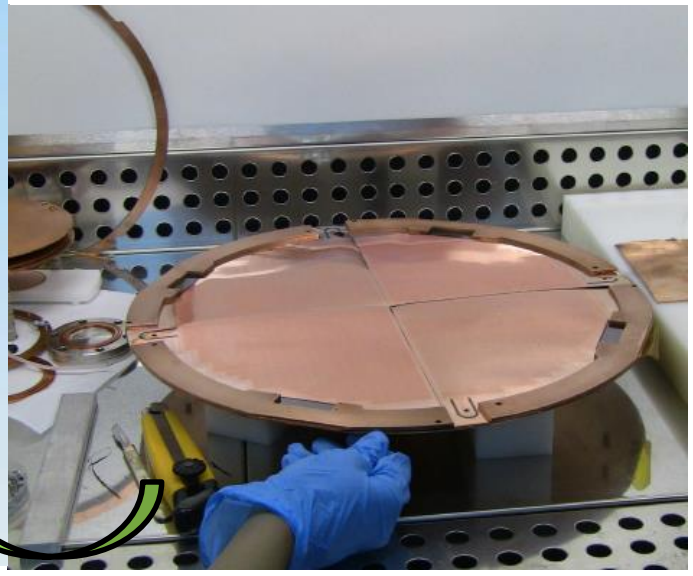
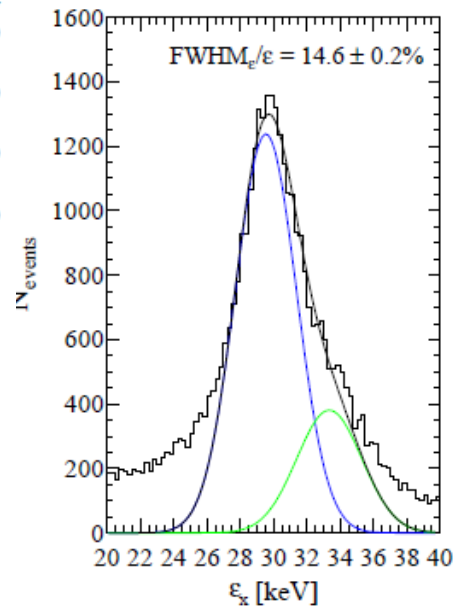
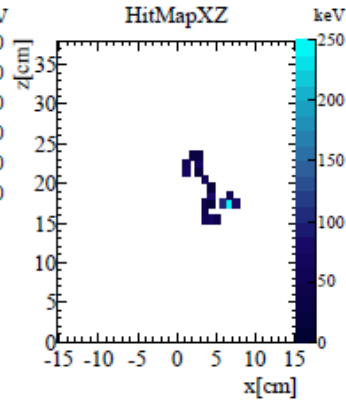
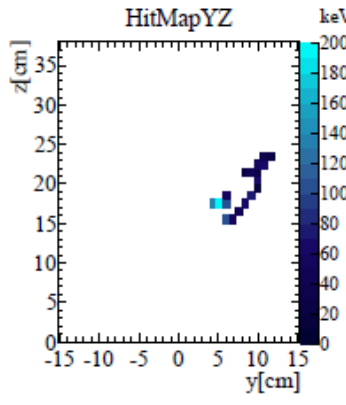
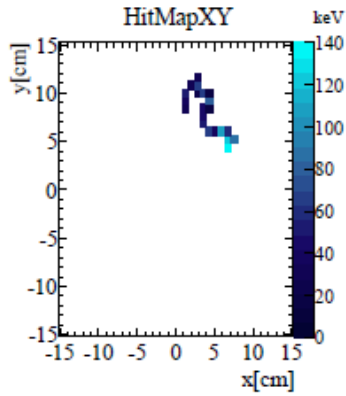
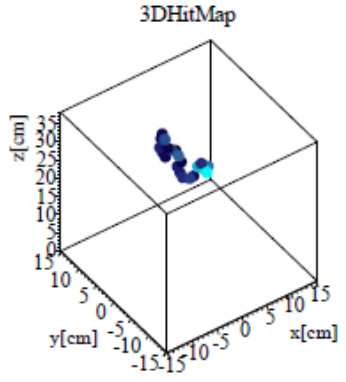
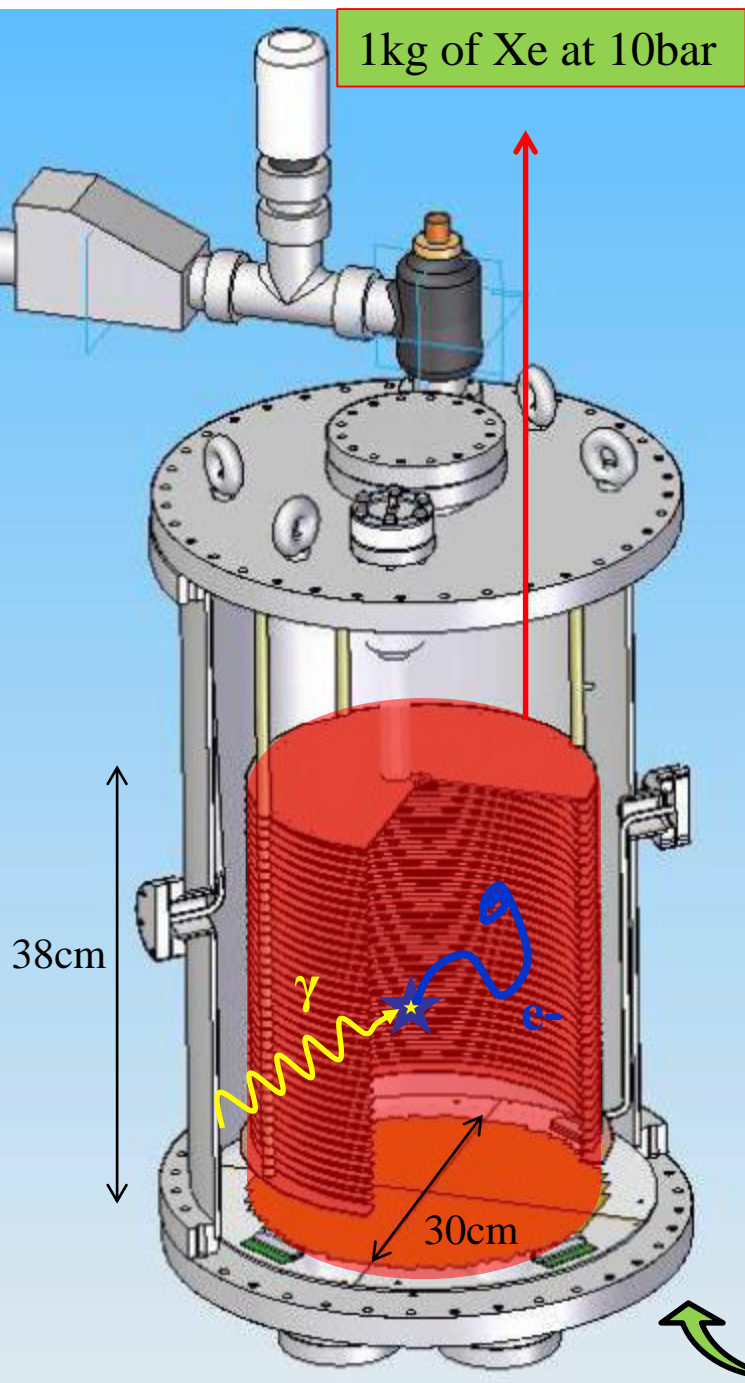
E. Ruiz-Choliz (Zaragoza University)
and

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on behalf of the Zaragoza group
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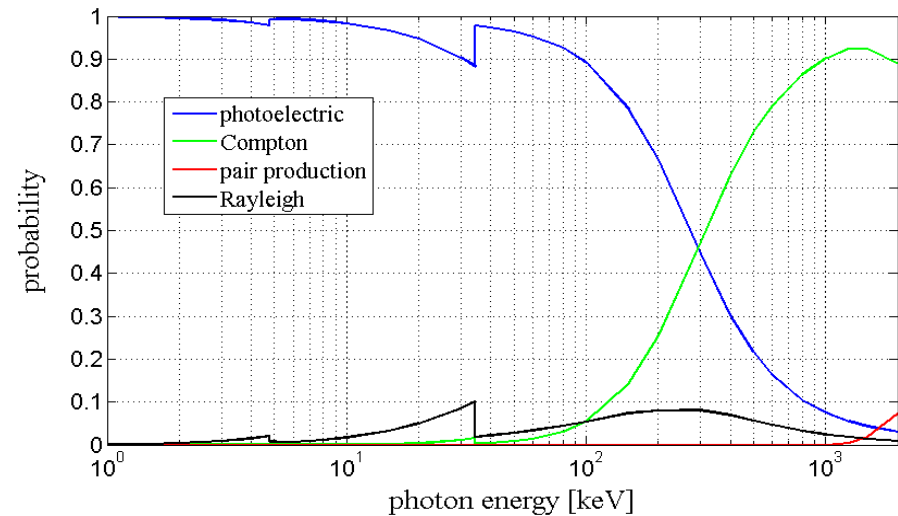
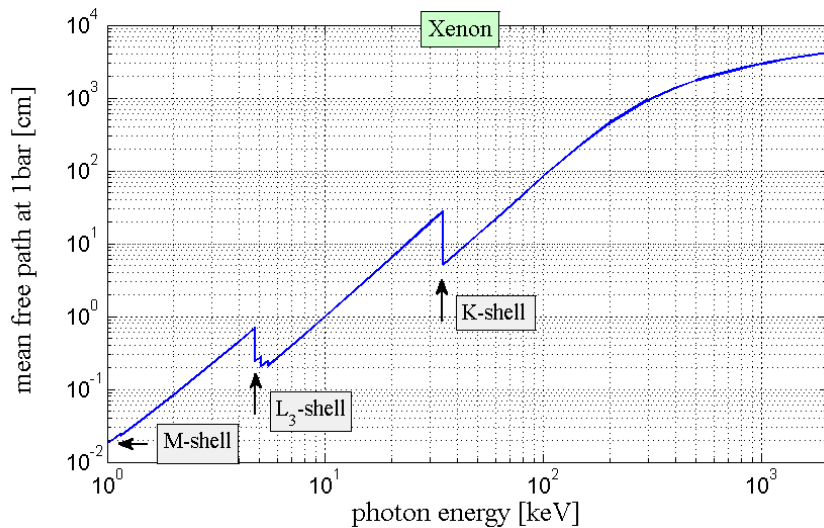
CERN, 12-06-2015

what we wanted to understand:

1kg of Xe at 10bar



What we knew:



What we did not know:

1. Track topology \leftrightarrow Characteristics of the primary electron ionization trail.
2. Drift properties \leftrightarrow Properties of electron ionization trail in electric field:
diffusion, drift, attachment.
3. Readout properties \leftrightarrow Properties of multiplication structures:
transmission, energy resolution, gain.

simulation code

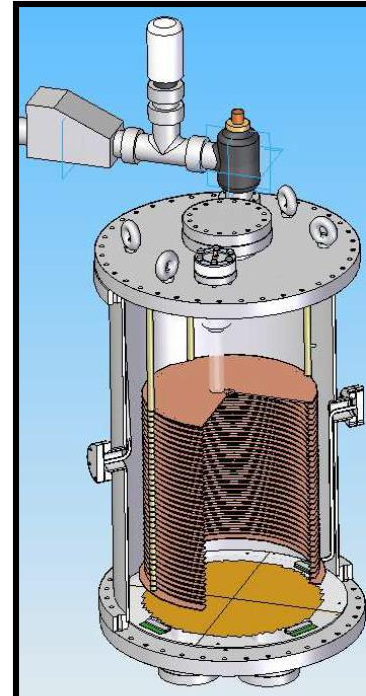
(DEGRAD)

Magboltz

Garfield++

+ recombination and Penning transfer processes

1. Drift data from the 38cm x 700cm²-setup (NEXT-MM)

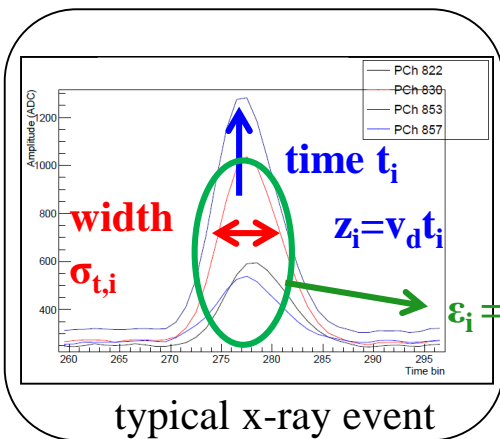


drift properties

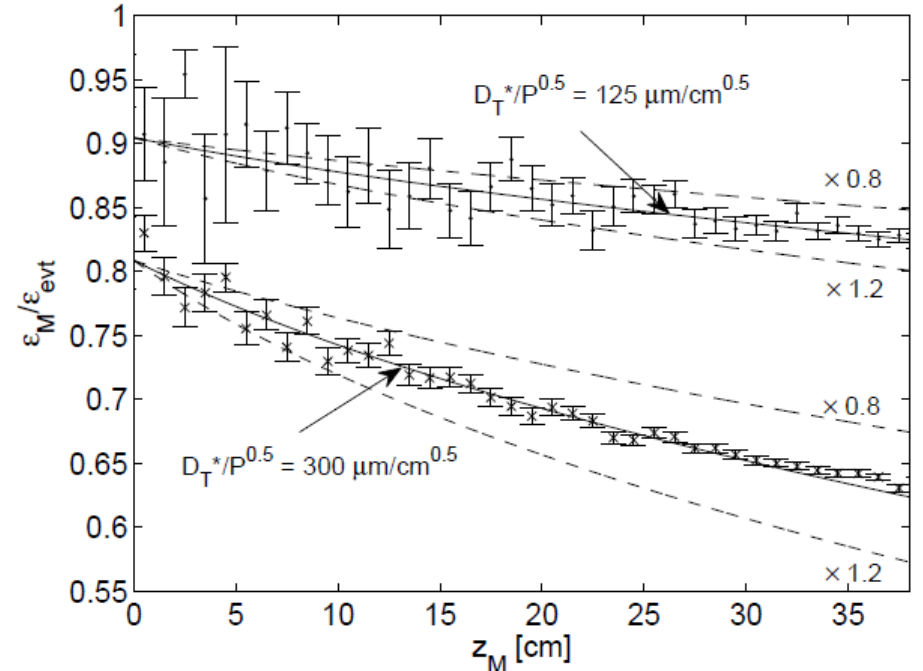
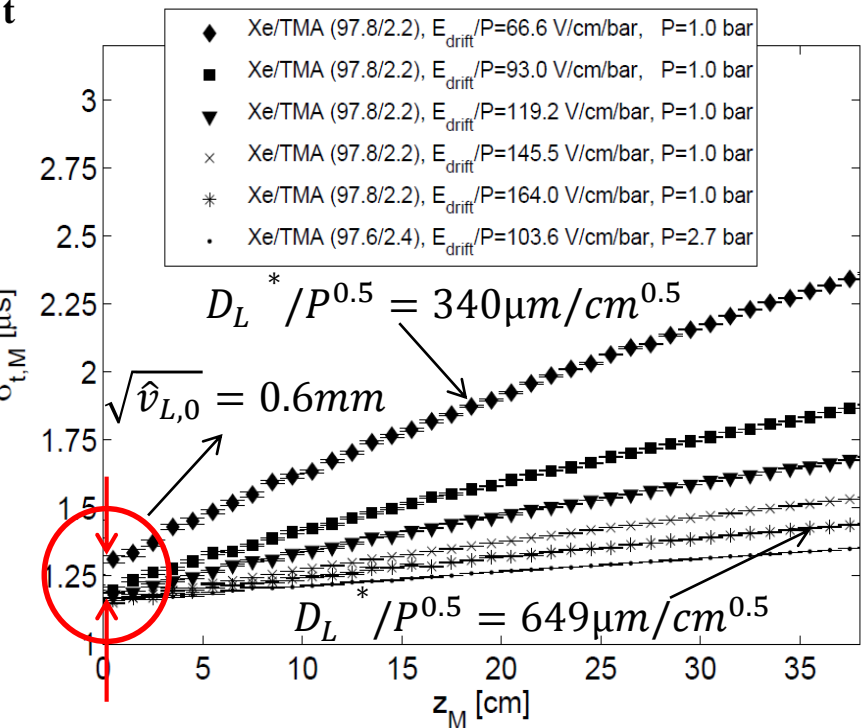
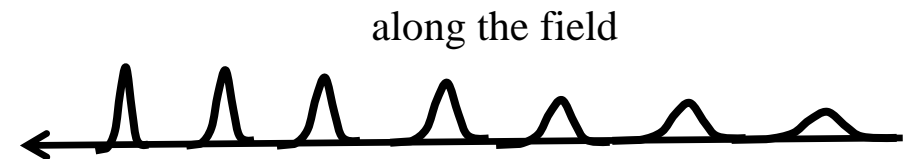
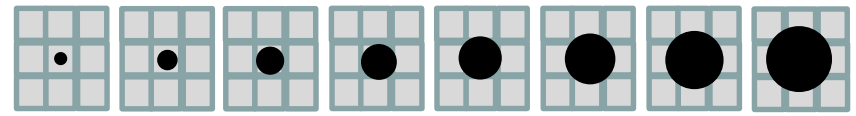
$$D_L^* = \sqrt{\frac{T_0}{T} \frac{2P}{v_d} \frac{D_L}{v_d}} \left[\frac{\mu\text{m}}{\sqrt{\text{cm}}} \times \sqrt{\text{bar}} \right]$$

agreement with Magboltz??

$$\sigma_{L,T} = D_{L,T}^* \frac{\sqrt{z}}{\sqrt{P}}$$



across the field

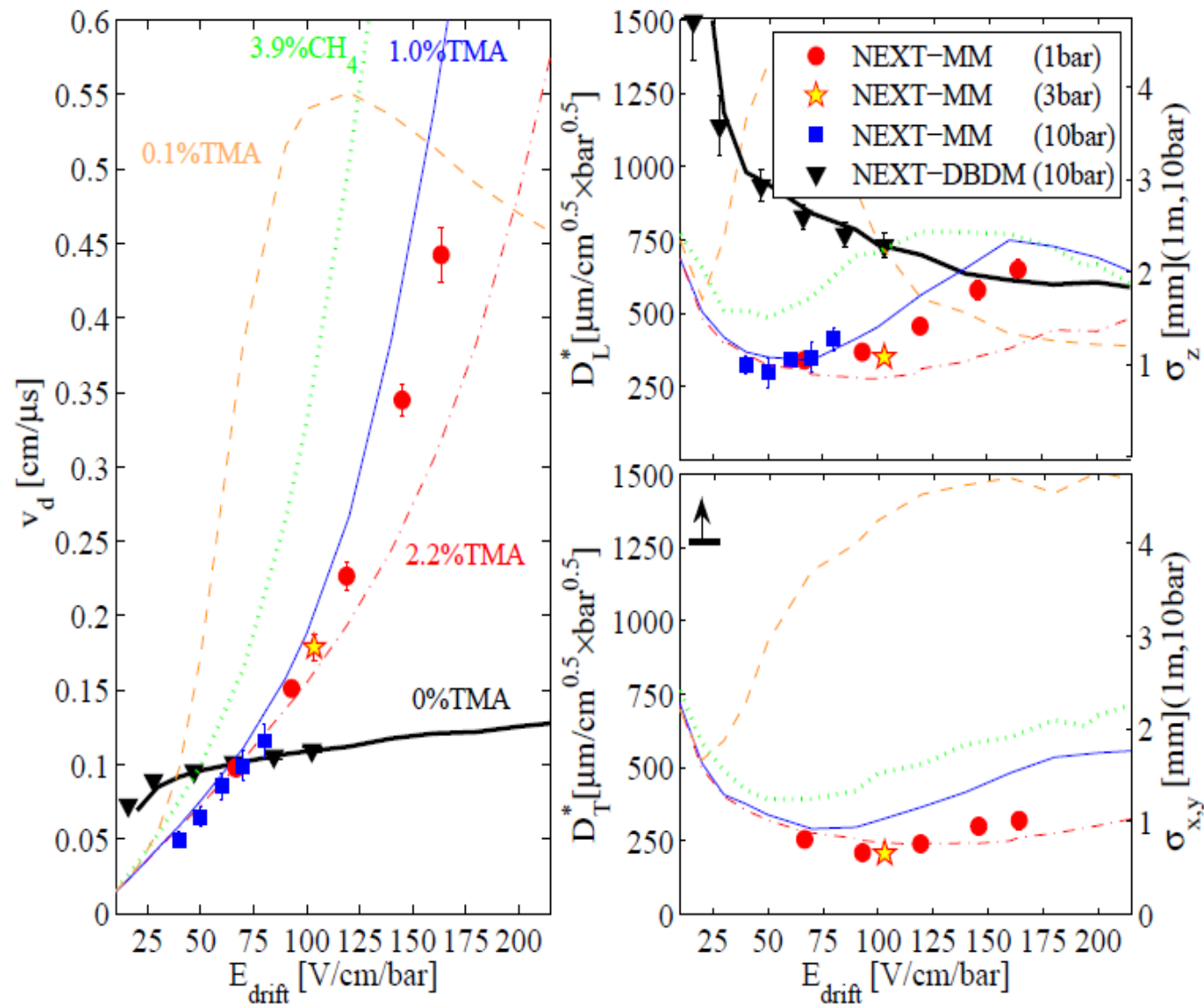


$$\left\langle \frac{\epsilon_M}{\epsilon_{\text{evt}}} \right\rangle = \frac{\left[2\hat{v}_r \left(e^{-\frac{L^2}{2\hat{v}_r}} - 1 \right) + \sqrt{2\pi}L\sqrt{\hat{v}_r} \text{erf} \left(\frac{L}{\sqrt{2\hat{v}_r}} \right) \right]^2}{2\pi L^2 \hat{v}_r}$$

$$\hat{v}_r = D_T^{*2} \times \frac{z_M}{P} + \hat{v}_{r,0} \longrightarrow \sqrt{\hat{v}_{r,0}} = 1 \pm 0.1\text{mm}$$

drift properties (data and Magboltz simulation)

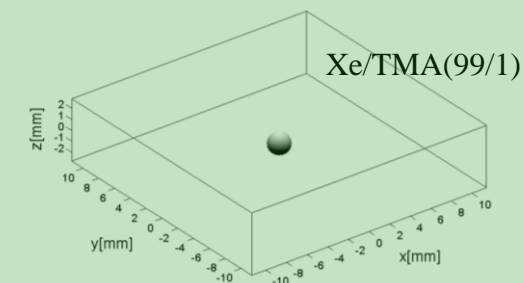
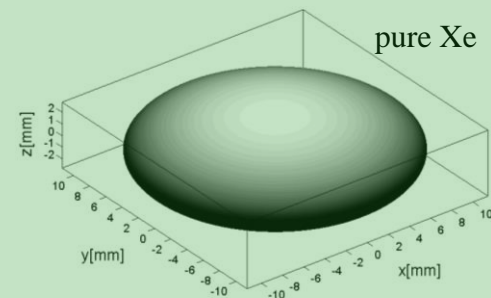
parameters of the electron swarm for Xenon-TMA admixtures



$$\sigma_{z,xy} = D_{L,T}^* \frac{\sqrt{z}}{\sqrt{P}}$$

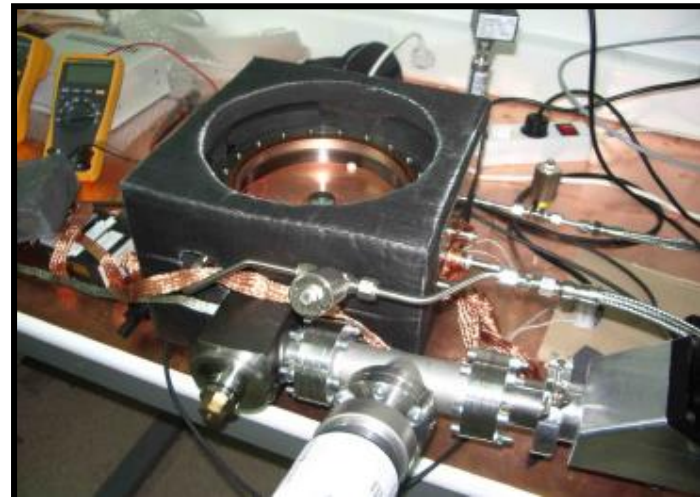
Spatial spread of point-like charge deposits

$z_{drift} = 100$ cm, $P = 10$ bar



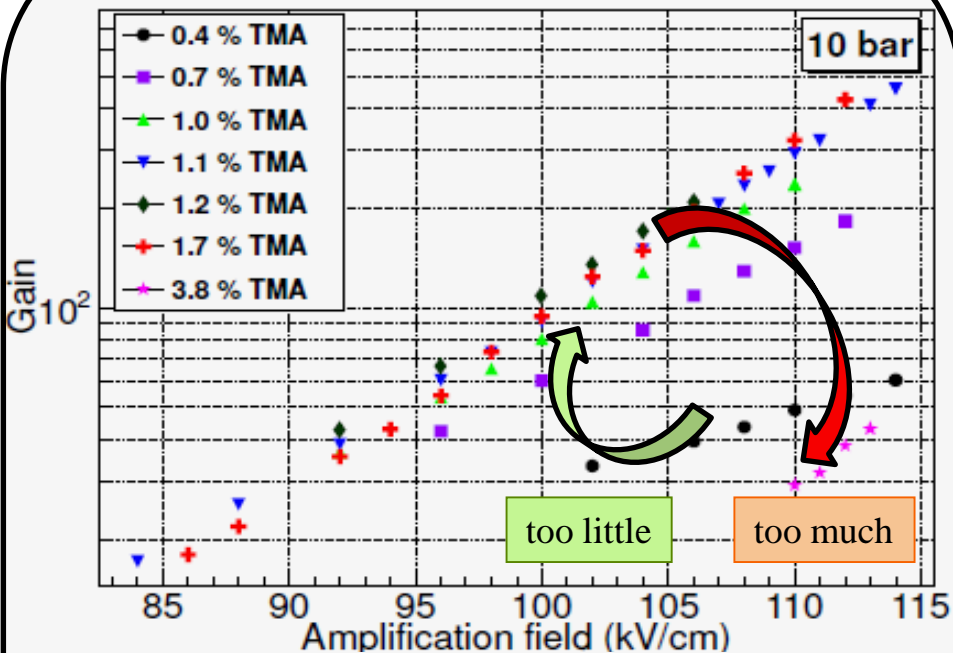
$E_{drift} \sim 50-100$ V/cm/bar

2. Data from the 1cm x 10cm²-setup (NEXT-MM0)

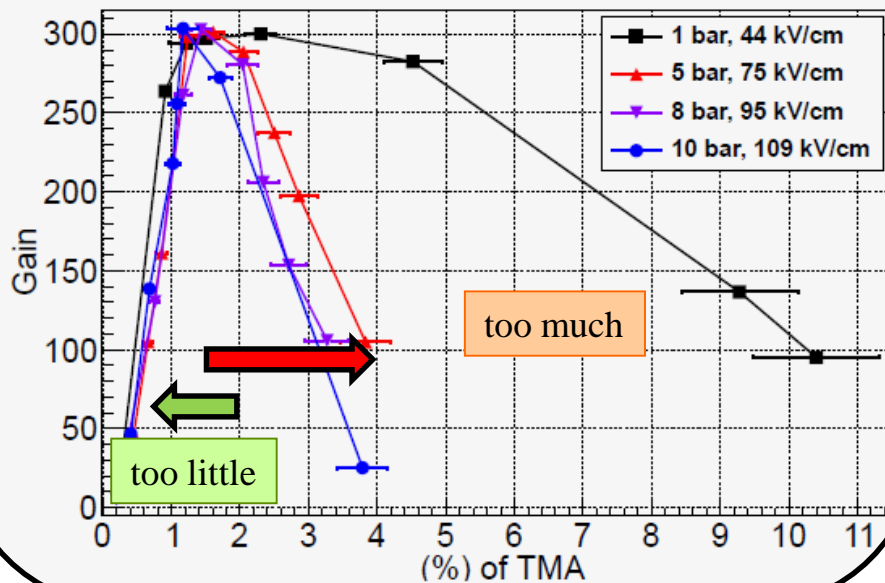
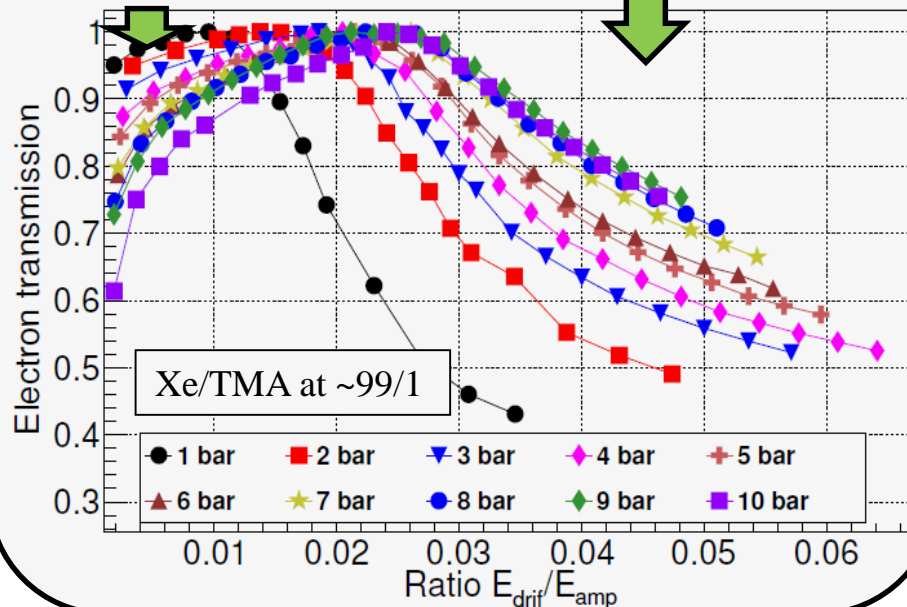


charge readout properties

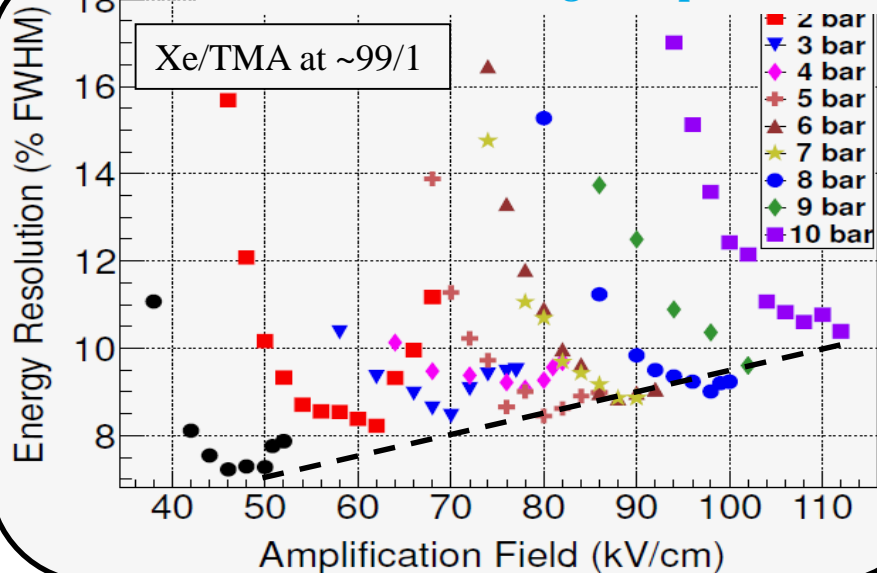
clear indication of *Penning* effect!



reduction of field flux through holes?
recombination?



resolution worsening with pressure?



electric field modelling (3D) and Garfield++

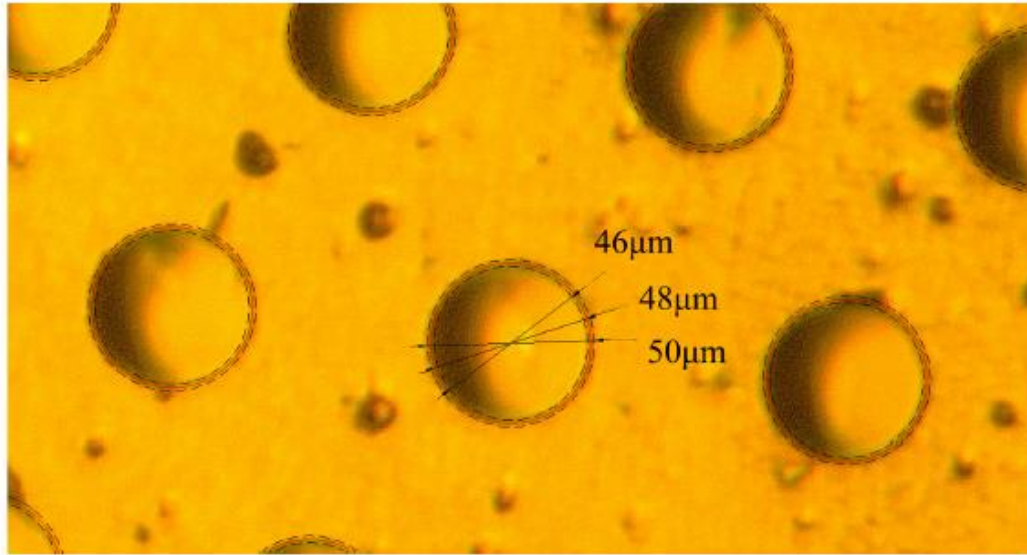
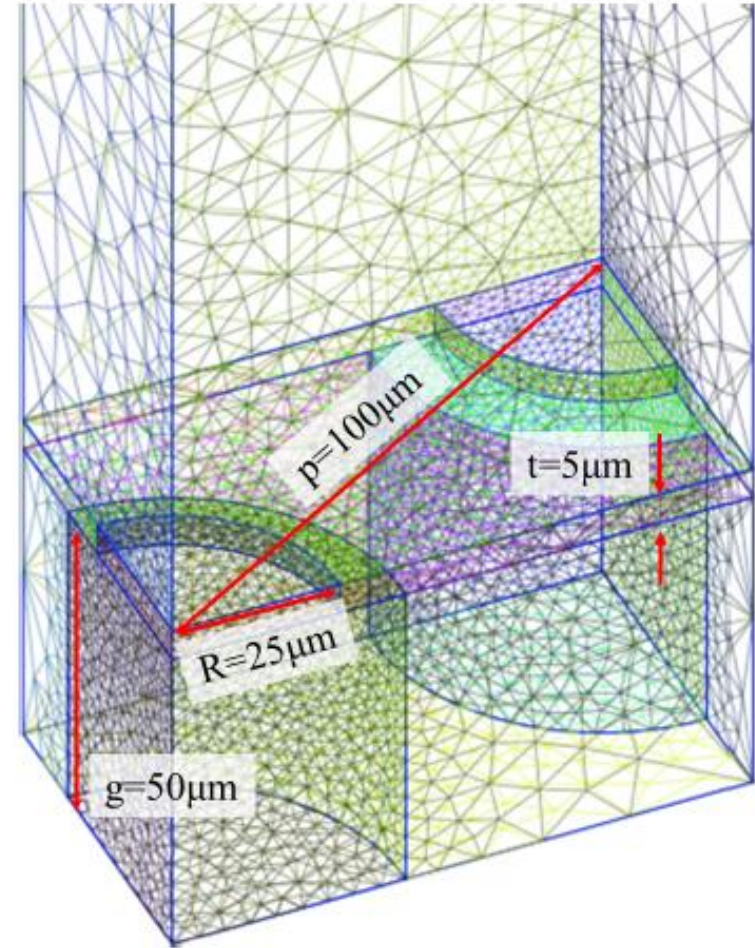
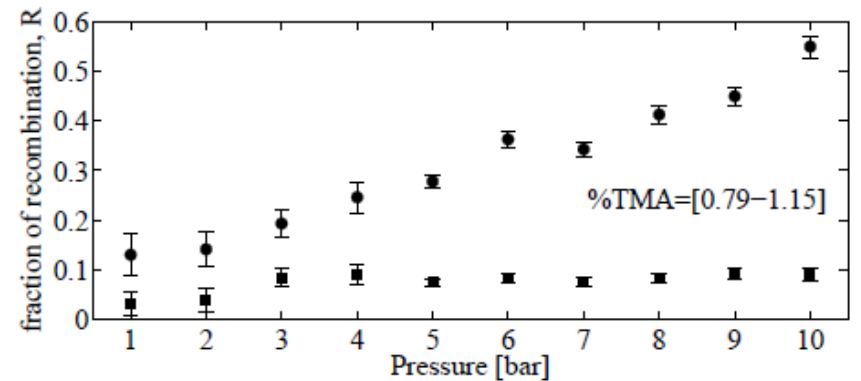
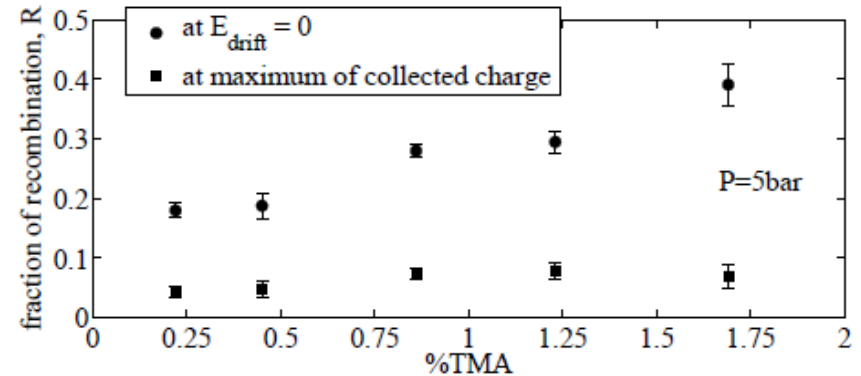
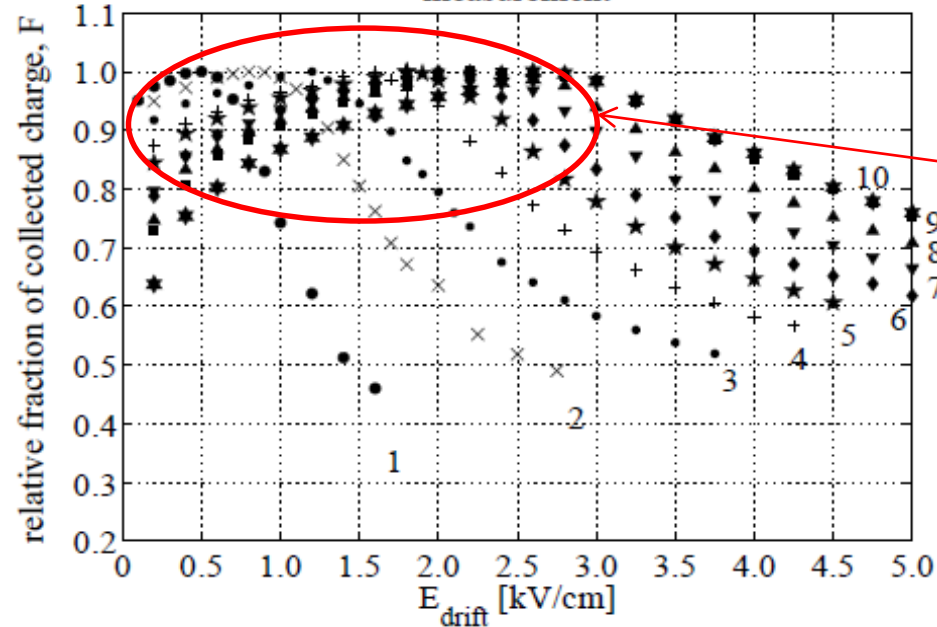
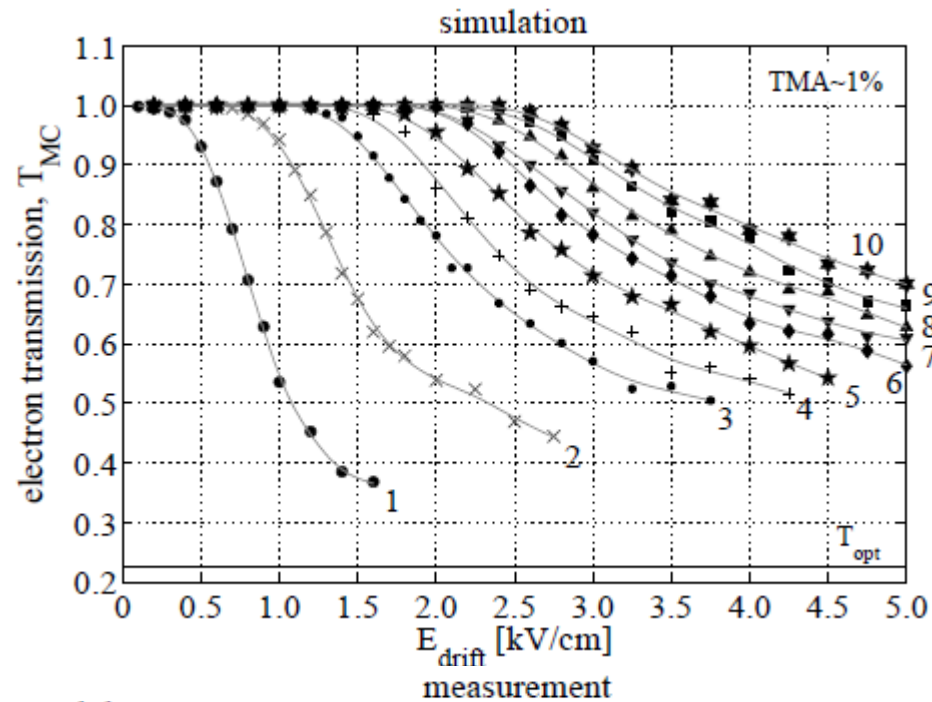


Fig. 1. Microscope image of the surface of the microbulk Micromegas whose performance has been simulated in this work. The surface characteristics are determined by the gold coating. The dashed circles represent the biggest and smallest circles compatible with the hole foot-print. The (red) continuous circle has the average diameter of both, yielding an estimate of $\phi = 48\mu\text{m} \pm 2\mu\text{m}$.



Gmsh + ELMER
(Garfield++ interface provided by J. Renner)

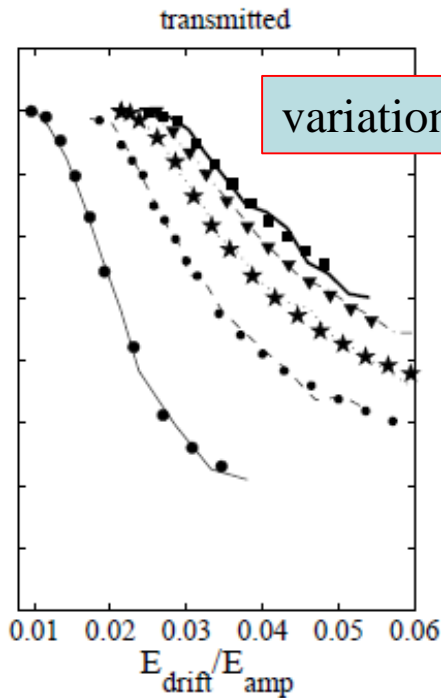
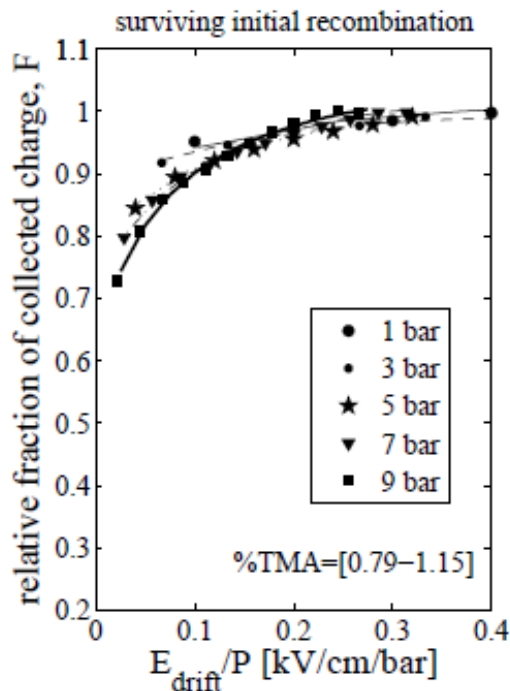
fraction of collected charge/electron transmission



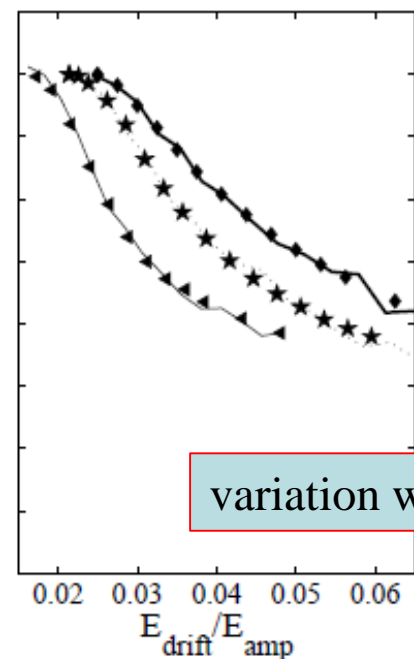
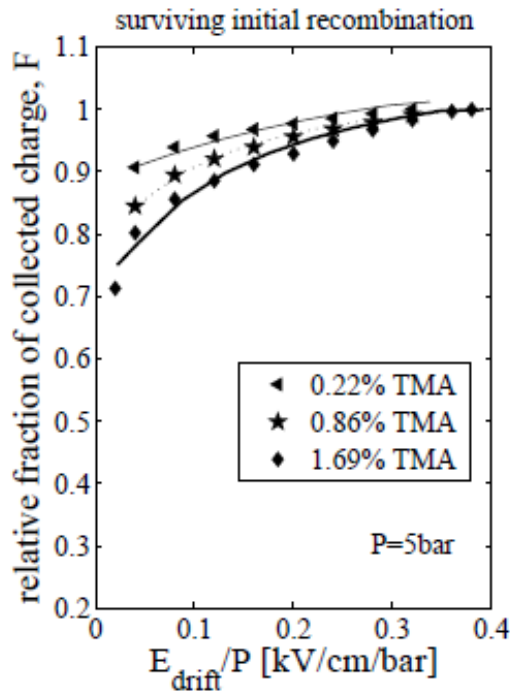
$$\mathcal{R}(E_d/P) = \left(1 - \frac{Q_0}{Q_\infty}\right) \left(1 - \frac{1}{1 + kP/E_d}\right)$$

(measured attachment <0.1%)

➔ $\mathcal{F}(E_d, E_a) = \frac{(1 - \mathcal{R})T}{\max[(1 - \mathcal{R})T]}$?



variation with pressure



variation with concentration

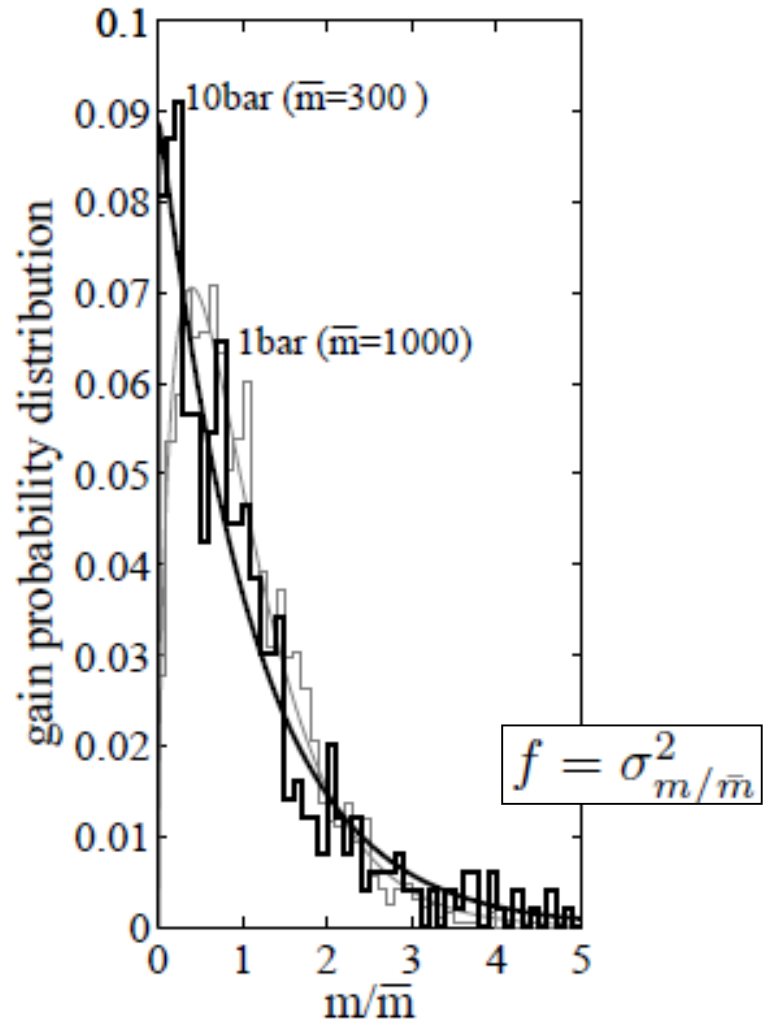
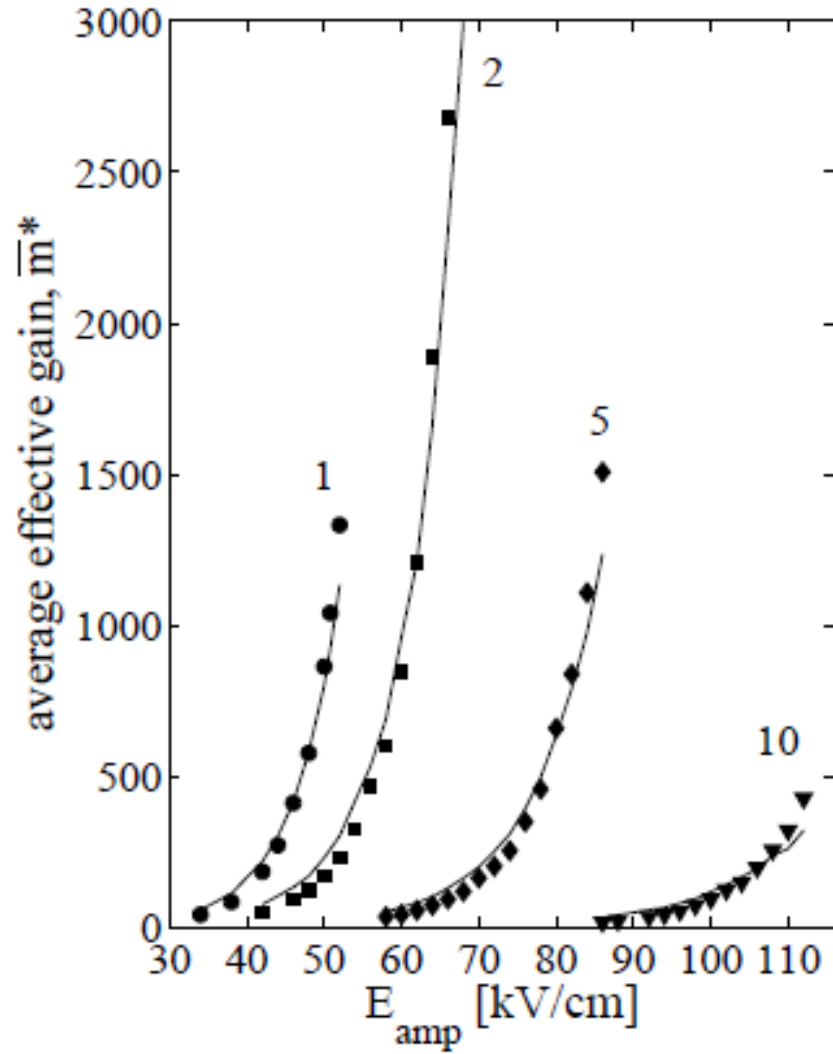


(global fit to data)

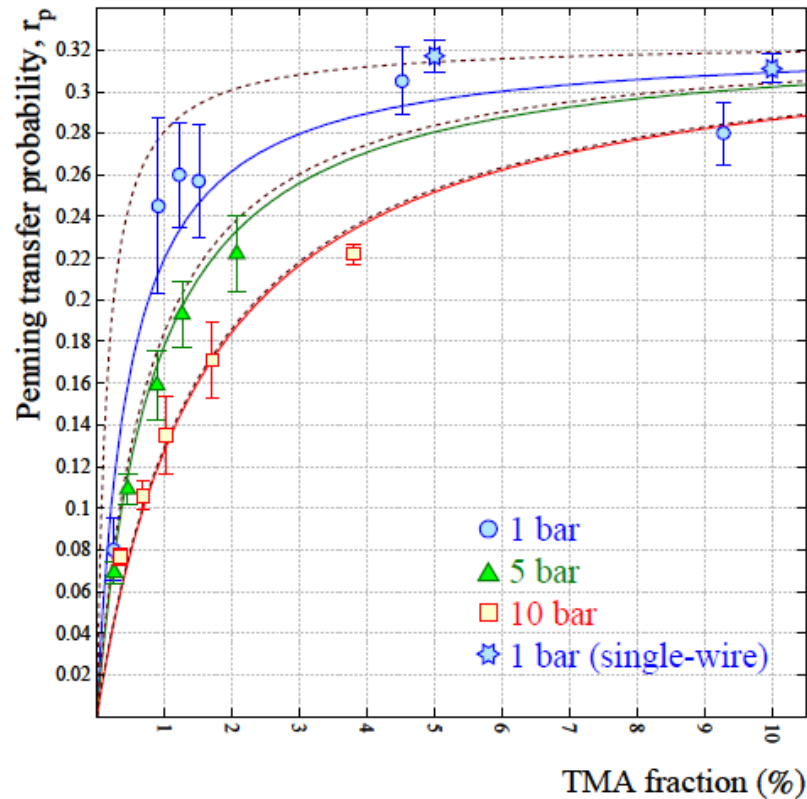
$$\mathcal{F}(E_d, E_a) = \frac{(1 - \mathcal{R})\mathcal{T}}{\max[(1 - \mathcal{R})\mathcal{T}]}$$

effective gain

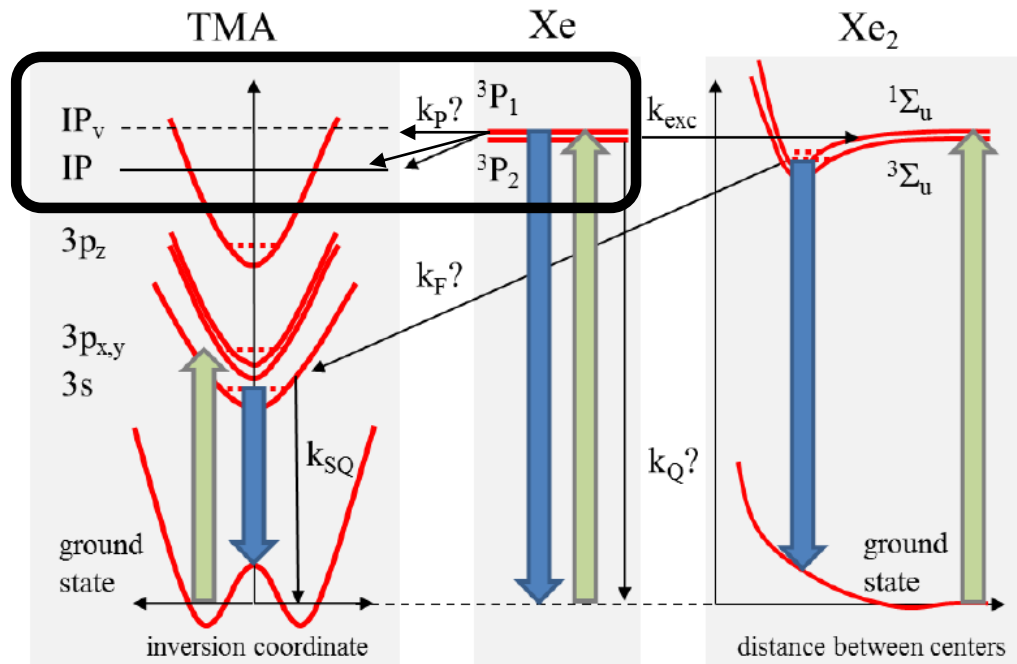
$$\bar{m}^* = \mathcal{T}(1 - \mathcal{R}) \times \bar{m} \quad (\bar{m} \equiv f(r_p))$$



Penning transfer probability



simplified level diagram including only low-lying states



Simplified model (only Xe* singlet-state can make the transfer):

$$r_p = \frac{cP}{(1-c)^2 P^2 a_1 + cP a_2 + a_3}$$

$$\tau_1^* = \frac{a_1}{a_3} \frac{1}{k_{exc,1}} = 9.2 \pm 2.5 \text{ ns}$$

$$r_p = f_1 \frac{cP k_{p,1}}{(1-c)^2 P^2 k_{exc,1} + cP(k_{p,1} + k_{Q,1}) + 1/\tau_1^*} + f_3 \frac{cP k_{p,3}}{(1-c)^2 P^2 k_{exc,3} + cP(k_{p,3} + k_{Q,3})}$$

energy resolution (for 22keV X-rays)

Not viable to simulate $22\text{keV}/W_I \sim 900$ primary electrons, we assume independent fluctuations:

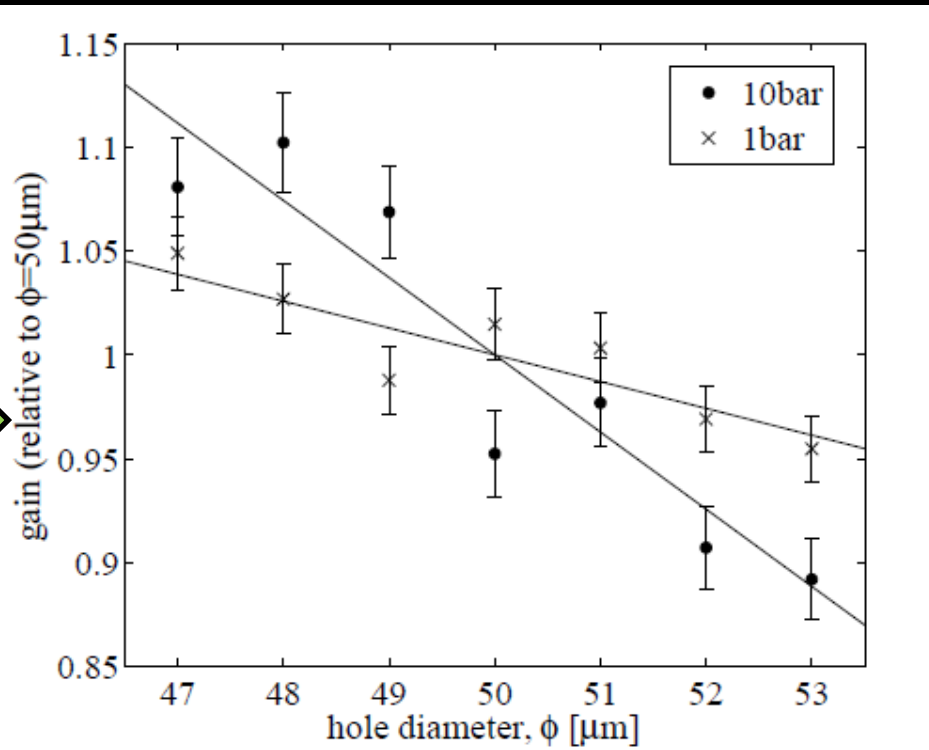
$$\mathfrak{R} = 2.35 \sqrt{\sigma_{int}^2 + \sigma_{mech}^2 + \sigma_{S/N}^2}$$

$$\sigma_{int} = \sqrt{F + f + TR + (1 - T)} \frac{1}{\sqrt{n_e}}$$

$$\sigma_{mech} = \left| \frac{1}{\bar{m}} \frac{dm}{d\phi} \right| \sigma_\phi$$

$$\sigma_{S/N} = \frac{ENC}{\bar{m}} \frac{1}{n_e}$$

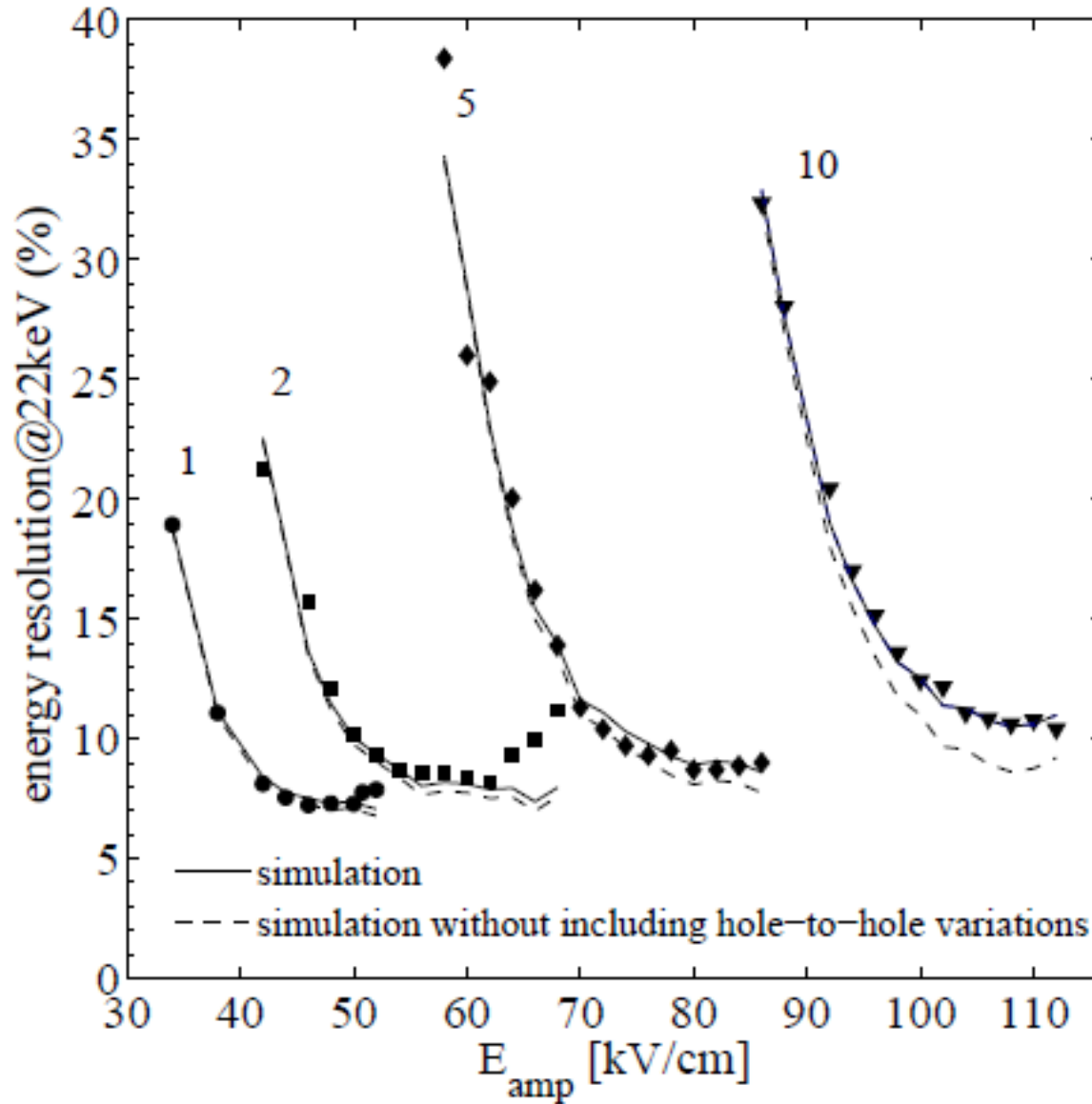
$$n_e = (1 - \mathcal{R}) T \frac{\varepsilon}{W_I}$$



Higher sensitivity at high pressure!

P [bar]	gain	$-\frac{1}{\bar{m}} \frac{dm}{d\phi}$ [%/ μm]
1	350	1.1 ± 0.3
1	1350	1.3 ± 0.4
10	100	3.0 ± 0.6
10	150	3.7 ± 0.8

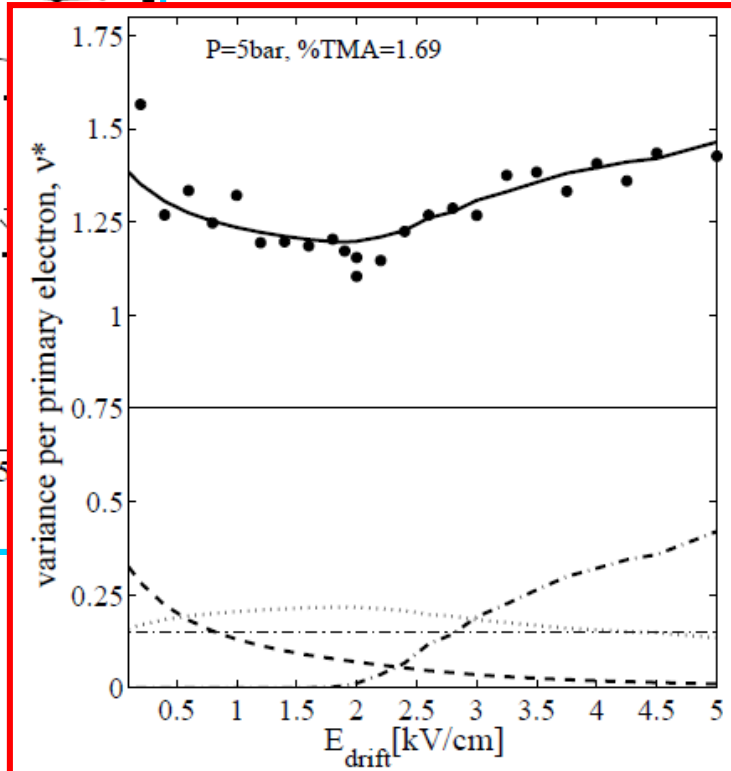
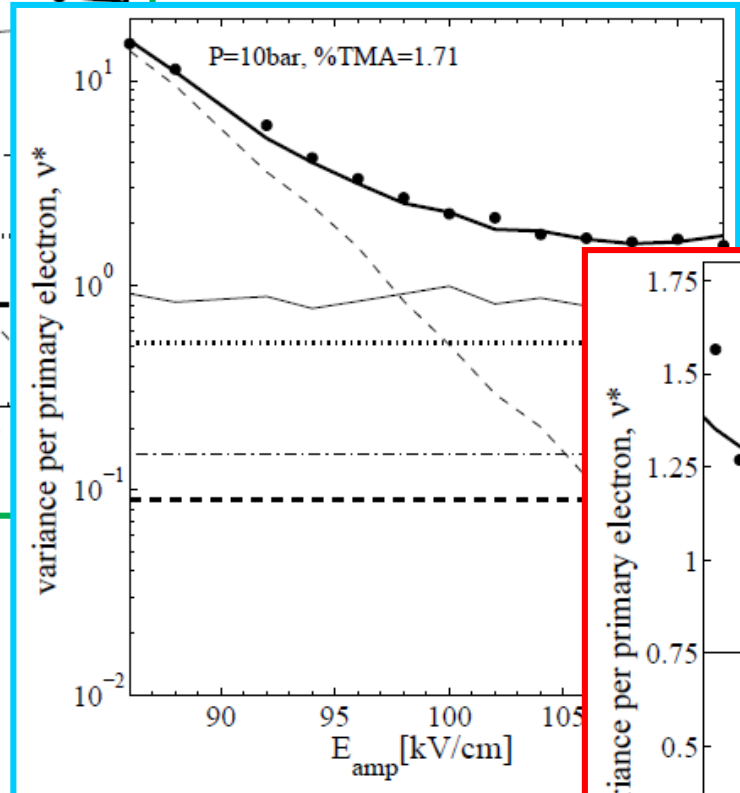
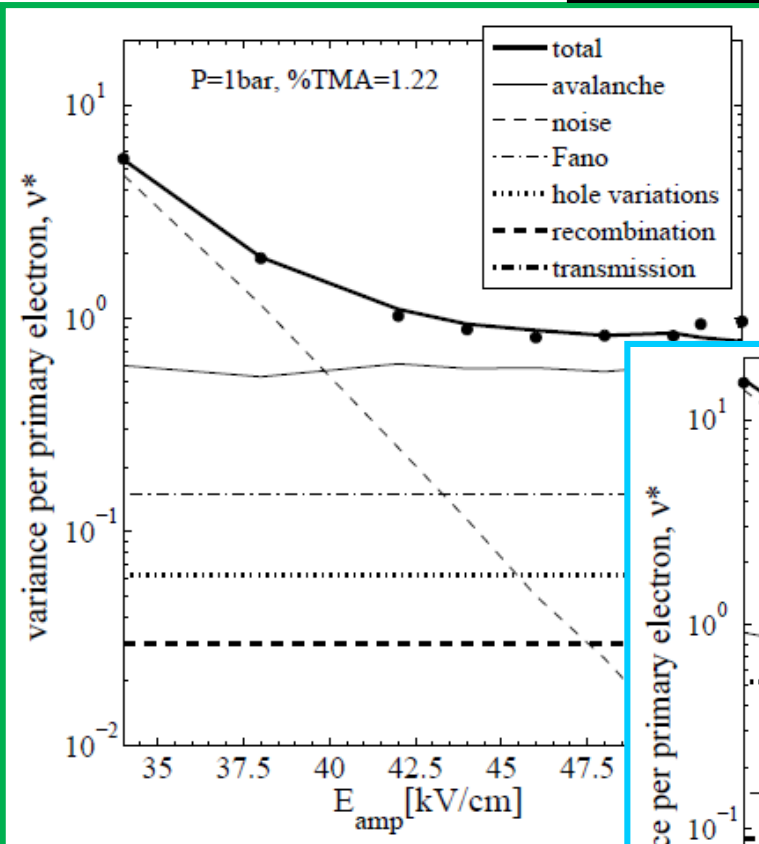
comparison with data (I)



$$\sigma_{\phi} = 0.6 \mu\text{m}$$

comparison with data (II)

$$v^* = \left(\frac{\mathfrak{R}}{2.35} \right)^2 n_e$$



extraction of Fano factor (1bar)

$$v^* = \left(\frac{\mathfrak{R}}{2.35} \right)^2 n_e$$

$$\mathfrak{R}_p = \sqrt{\frac{n_e}{n_{e,p}} \mathfrak{R}^2 - 2.35^2 \frac{(F - F_p)}{n_{e,p}}}$$

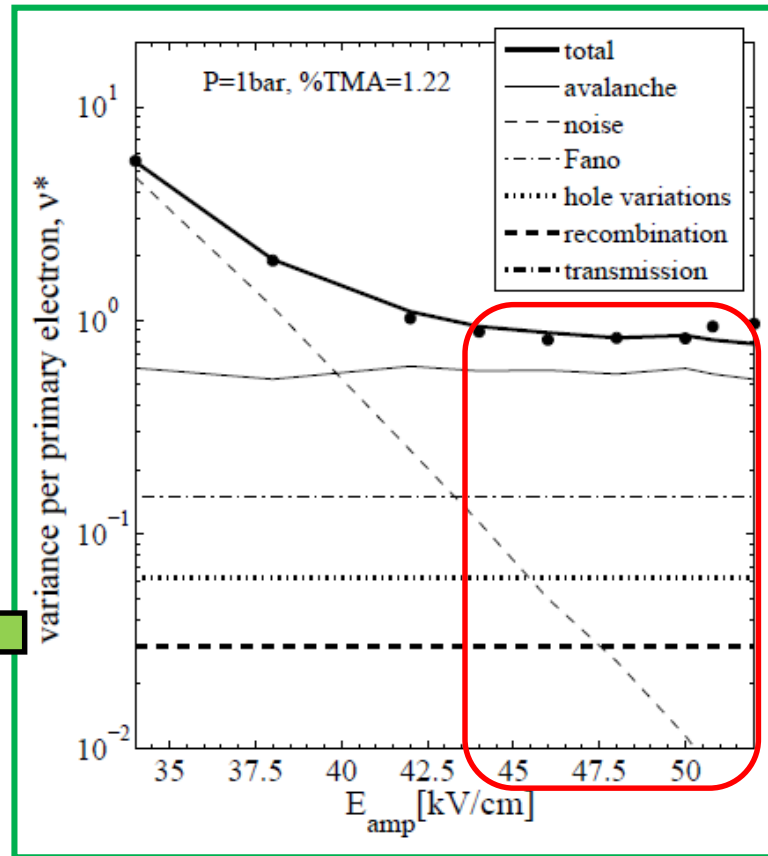
$$\frac{n_{e,p}}{n_e} = 1 + \frac{N_{ex}}{N_I} r_p(E_d)$$

$$\frac{n_{e,p}}{n_e} = 1 + \frac{W_I}{W_{sc}} r_p = 1.10 \pm 0.04$$

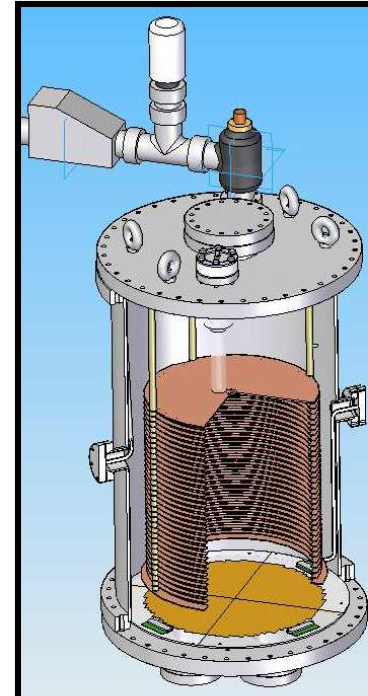
$$F_p = \frac{n_{e,p}}{n_e} v^* - f - \mathcal{T}\mathcal{R} - (1 - \mathcal{T}) - \sigma_{mech} - \sigma_{S/N} = 0.20 \pm 0.06$$



$$\mathfrak{R}_{0, Xe-TMA} = 2.35 \sqrt{\frac{F_p}{n_{e,p}}} = (0.50\% \pm 0.08\%) \sqrt{\frac{1\text{MeV}}{\epsilon}}$$

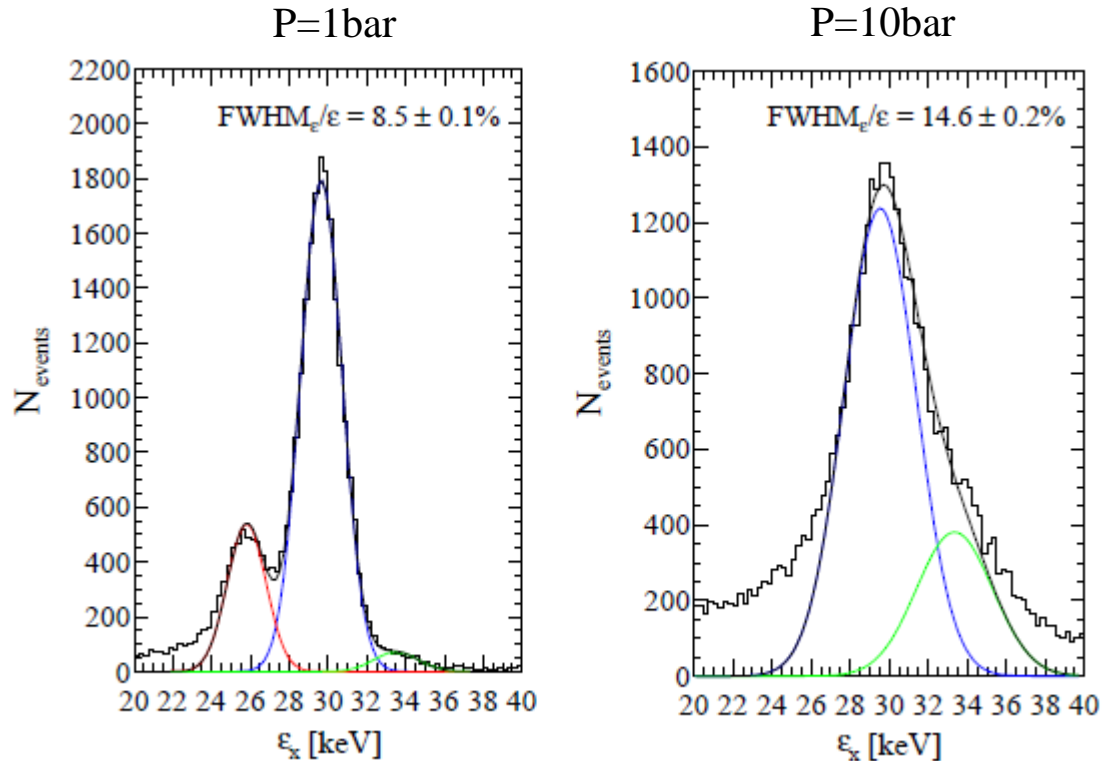


3. Energy resolution data from the 38cm x 700cm²-setup (NEXT-MM)

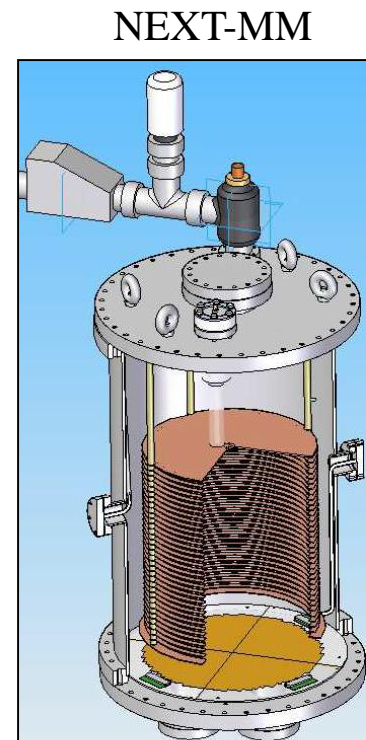


understanding the energy resolution in a realistic system (I)

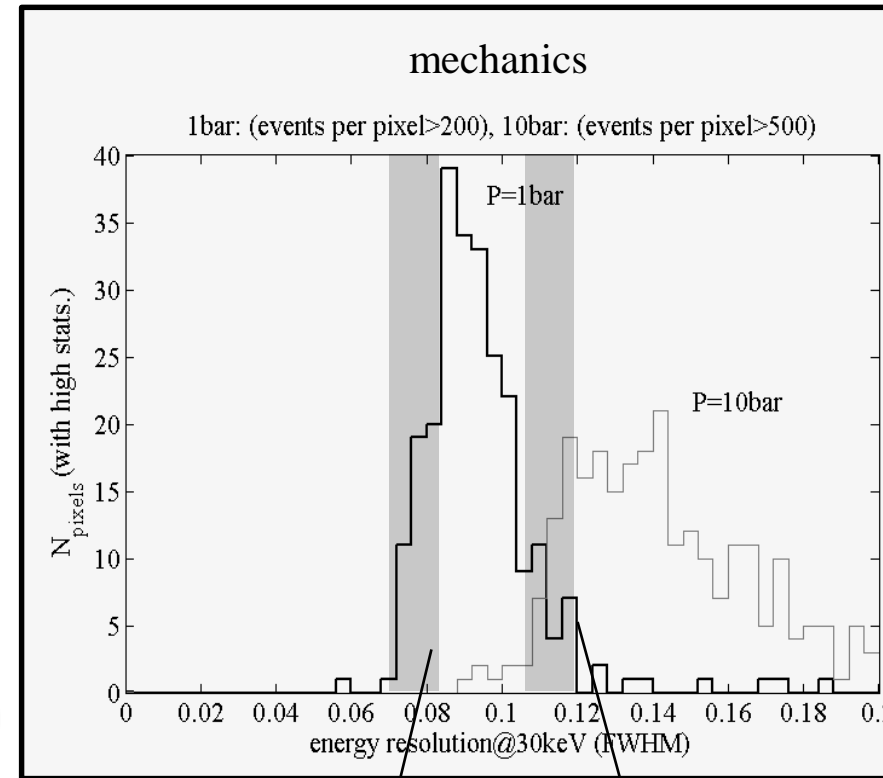
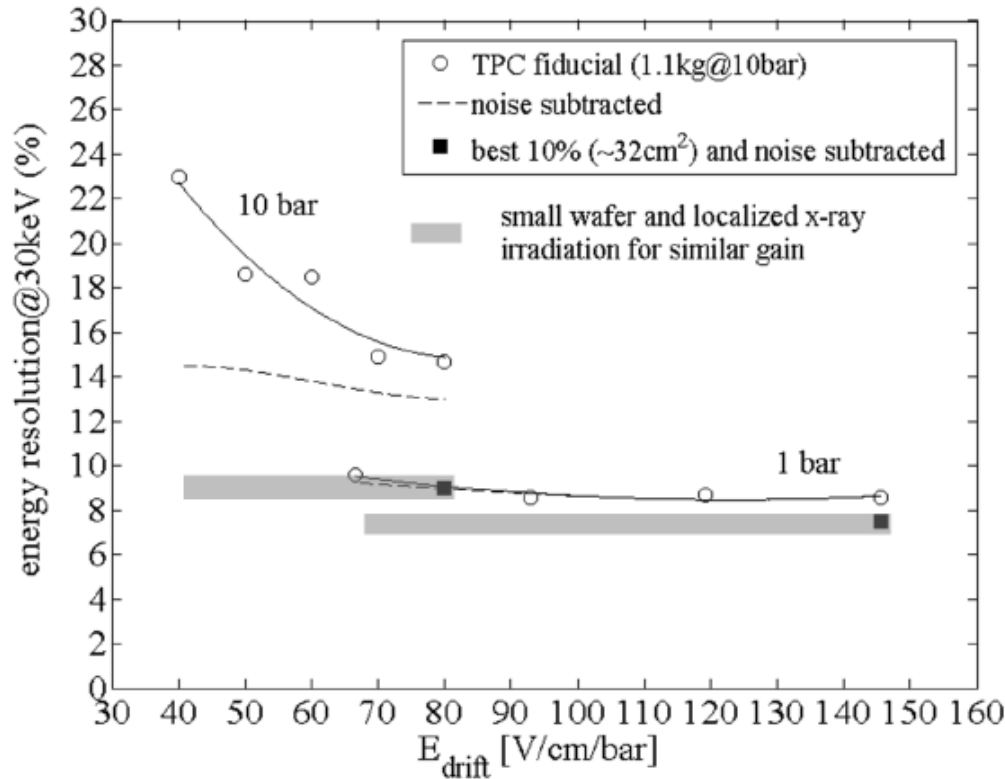
$$\mathfrak{R} = 2.35 \sqrt{\sigma_{int}^2 + \sigma_{mech}^2 + \sigma_{S/N}^2}$$



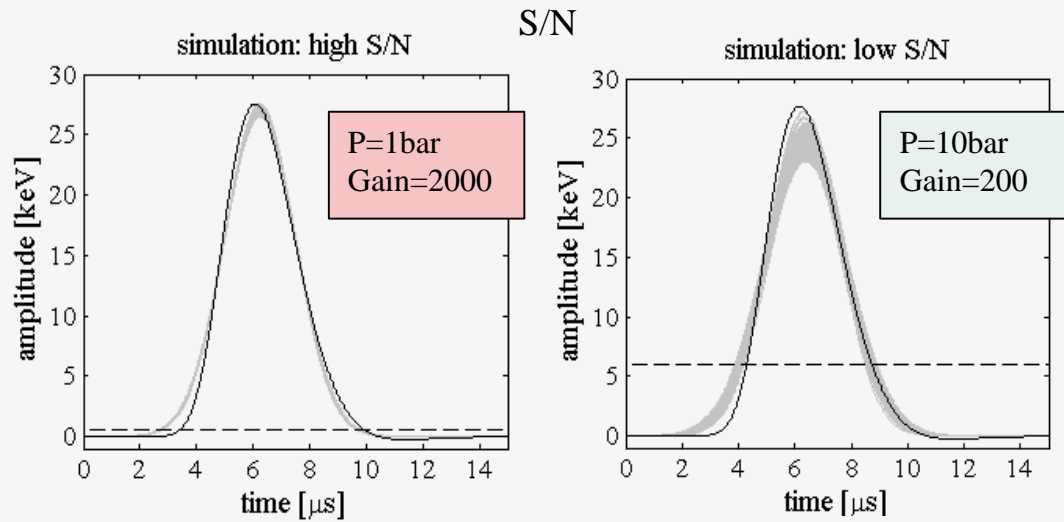
can be understood in terms of the contributions identified in the small setup ?



understanding the energy resolution in a realistic system (II)

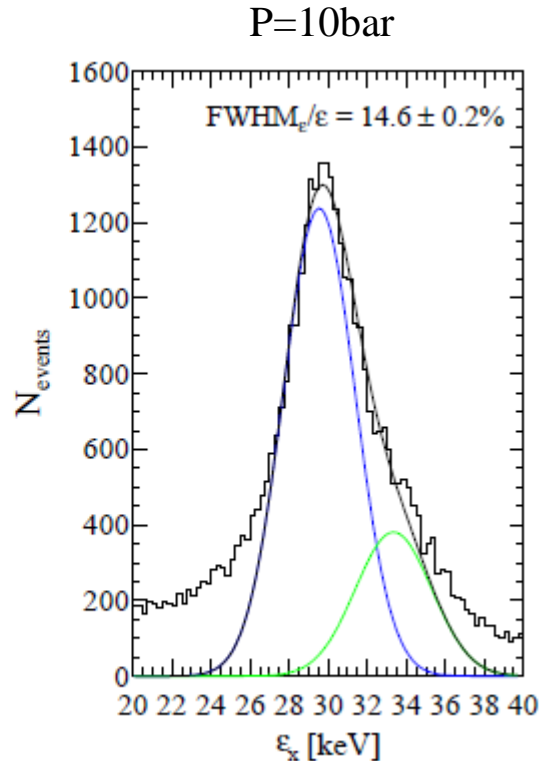
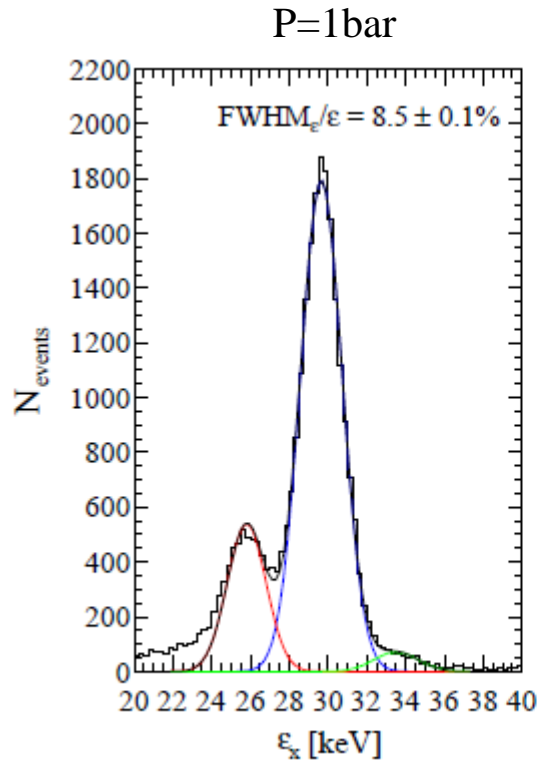


best 10% $\rightarrow \sigma_{\text{intr}}^2 + \sigma_{S/N}^2$



understanding the energy resolution in a realistic system (III)

$$\mathfrak{R} = 2.35 \sqrt{\sigma_{int}^2 + \sigma_{mech}^2 + \sigma_{S/N}^2}$$



$$\sigma_{int} = 0.075$$

$$\sigma_{S/N} = 0.002$$

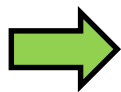
$$\sigma_{mech} = 0.035$$

$$\sigma_{int} = 0.09$$

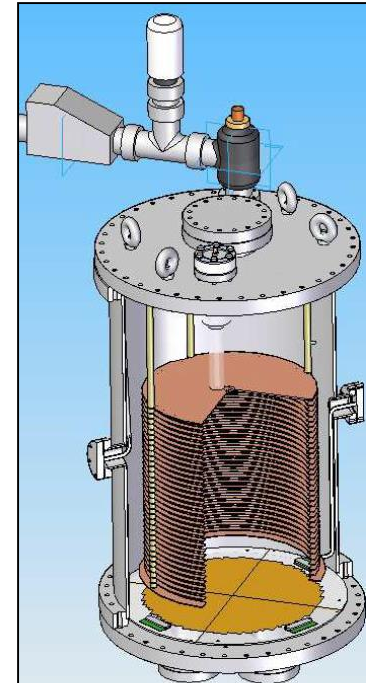
$$\sigma_{S/N} = 0.07$$

$$\sigma_{mech} = 0.09$$

$$\sigma_{\phi} = 1.0 \mu\text{m}$$



NEXT-MM



conclusions

1. 'Electron transmission' at high pressures requires both recombination (drift region) and hole-transmission (readout region) to be included. Measured data can be described by combining a recombination model (Bolotnikov, Ramsey) and the simulated electron transmission.
2. Penning-effect in Xe-TMA can be interpreted through a simple model that assumes resonant energy transfer from the Xe^* singlet state to TMA.
3. Energy resolution well explained by known sources except for a small deviation at high pressure.



Strong evidence of sensitivity to mechanical variations in the hole diameter at $0.5\mu\text{m}$ level! (important at 10bar)

appendix

